



Customer Information Notification

202104022I : MC33771x and MC33772x Safety Manual Updates - Apr2021

Note: This notice is NXP Company Proprietary.

Issue Date: Apr 12, 2021 **Effective date:** Apr 13, 2021

Dear Gordon Love,



Here is your personalized notification about a NXP general announcement.
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Change Category

- | | | | | |
|--|---|--|---|---|
| <input type="checkbox"/> Wafer Fab Process | <input type="checkbox"/> Assembly Process | <input type="checkbox"/> Product Marking | <input type="checkbox"/> Test Process | <input type="checkbox"/> Design |
| <input type="checkbox"/> Wafer Fab Materials | <input type="checkbox"/> Assembly Materials | <input type="checkbox"/> Mechanical Specification | <input type="checkbox"/> Test Equipment | <input type="checkbox"/> Errata |
| <input type="checkbox"/> Wafer Fab Location | <input type="checkbox"/> Assembly Location | <input type="checkbox"/> Packing/Shipping/Labeling | <input type="checkbox"/> Test Location | <input type="checkbox"/> Electrical spec./Test coverage |
- Firmware Other: Safety Manual Updates (Clarifications)

PCN Overview

Description

NXP Semiconductors announces Safety Manual updates for the Battery Cell Controller IC products MC33771A, MC33771B, MC33771C, MC33772A and MC33772B associated with this notification. The revision history included in the updated documents provides a detailed description of the changes.

Current safety manuals include the SysRec 12 recommendation (in section “Useful recommendations for safety” - also called “Assumed application requirements” for MC33771C device), stating that cell balancing should be paused before making a cell voltage measurement. Unless otherwise specified, any safety mechanism requiring cell terminal measurement falls into this category. For clarification purpose, safety procedures that do not yet highlight this requirement have been updated to reflect the complete procedure in case of already active cell balancing.

This clarification has also been reflected in Application Note AN12637 revision 3 (“MC33771C and MC33772C based system timing optimization”).

Together with these updates, the IC behavior after thermal shut down was clarified in Safety Mechanism 11 (not applicable to MC33771A and MC33772A devices).

Safety Manuals have been updated as follows:
MC33771A new revision P
MC33771B new revision E

MC33771C new revision D
MC33772A new revision K
MC33772B new revision E

In order to comply with NDA requirements, updated Safety Manual documents are available either on request, or through the secure NXP DocStore portal: www.docstore.nxp.com

Corresponding ZVEI Delta Qualification Matrix ID: SEM-DS-02.

Reason

To announce the release of Safety Manual updates for the MC3377x Battery Cell Controller IC products.

Identification of Affected Products

Product identification does not change

Anticipated Impact on Form, Fit, Function, Reliability or Quality

No Impact on form, fit, function, reliability or quality

Data Sheet Revision

No impact to existing datasheet

Additional information

Additional documents: [view online](#)

Contact and Support

For all inquiries regarding the ePCN tool application or access issues, please contact NXP "Global Quality Support Team".

For all Quality Notification content inquiries, please contact your local NXP Sales Support team.

For specific questions on this notice or the products affected please contact our specialist directly:

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NXP Quality Management Team.

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